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SPANSION PATENT RIGHTS

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FUJITSU PATENT APPLICATIONS AND ISSUED PATENTS

FJ No.	JPO Application No.	JPO Filing Date	Registration Date	Title	Publication No.	Registration No.	Publication Date
89P02073	H 1- 54998	19890309	19990319	SEMICONDUCTOR DEVICE	H 2-236178	2900941	19900919
93-07392	H 5-286658	19931116	20030411	CURRENT MIRROR TYPE OSCILLATOR CIRCUIT	H 7-142964	3418435	02.06.1995
93-07809	H 5-329285	19931227	20030320	FLASH MEMORY	H 7-192480	3409404	28.07.1995
94-00077	H 6-115360	19940527	20030404	SEMICONDUCTOR DEVICE	H 7-321207	3414496	08.12.1995
94-05461	H 6-168270	19940720	20030404	SEMICONDUCTOR MEMORY	H 8- 32437	3414852	02.02.1996
93-01191	H 5-152249	19930623	20040416	SEMICONDUCTOR STORAGE DEVICE	H 7- 21792	3545010	24.01.1995
93-08115	H 5-313341	19931214	2004.07.23	NON-VOLTAGE SEMICONDUCTOR MEMORY	H 7-169287	3578478	04.07.1995
93-09804	H 5-310244	19931210	2004.07.09	ELECTRICALLY ERASABLE NON-VOLATILE SEMICONDUCTOR MEMORY	H 7-169280	3573477	04.07.1995
93-12588	H 6- 48084	19940318	20040416	NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND DATA READING METHOD THEREOF	H 7-262787	3544222	13.10.1995
93-12603	H 6- 48116	19940318	2004.03.19	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE	H 7-263507	3534815	13.10.1995
93-14364	H 6-113271	19940527	2004.04.09	FLASH MEMORY	H 7-320492	3541427	08.12.1995
94-03231	H 6-220387	19940914	2004.09.24	SEMICONDUCTOR MEMORY DEVICE	H 8- 87898	3599793	02.04.1996
94-05460	H 7- 30629	19950220	2004.06.25	SEMICONDUCTOR MEMORY DEVICE	H 8-221998	3568265	30.08.1996
94-07025	H 7- 2771	19950111	2004.04.16	NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	H 8-195090	3544731	30.07.1996
94-11161	H 7-155664	19950622	2003.08.29	DATA OUTPUT CIRCUIT AND SEMICONDUCTOR MEMORY DEVICE	H 9- 8640	3465416	10.01.1997
94-11600	H 7-190846	19950726	2004.05.28	METHOD AND EQUIPMENT FOR TESTING NONVOLATILE MEMORY	H 9- 45100	3558746	14.02.1997
95-00231	H 7-173097	19950710	2004.04.09	SEMICONDUCTOR MEMORY	H 9- 27195	3541503	28.01.1997
96-04915	H 9- 66790	19970319		SEMICONDUCTOR DEVICE AND ITS MANUFACTURE	H10-261726		29.09.1998
97-00692	H 9-211663	19970806	2004.11.05	MANUFACTURE OF SEMICONDUCTOR DEVICE	H11- 54638	3613312	26.02.1999
97-03900	H10- 66888	19980317		MANUFACTURE OF SEMICONDUCTOR DEVICE	H11-265994		28.09.1999
99-40161	H11-226913	19990810		MULTI-BIT NON-VOLATILE MEMORY UTILIZING NON-CONDUCTIVE CHARGE TRAP GATE	2001- 57093		27.02.2001

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99-40214	H11-334916	19991125		NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND ITS MANUFACTURING METHOD	2001-156272		08.06.2001
99-40253	H11-250780	19990903		SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURE THEREOF	2001- 77215		23.03.2001
99-40272	H11-294199	19991015		SEMICONDUCTOR MEMORY AND USAGE METHOD THEREFOR	2001-118940		27.04.2001
00-40262	2000-159102	20000529		SEMICONDUCTOR TESTER	2001-337128		07.12.2001
00-40755	2000-245859	20000814		METHOD FOR MANUFACTURING NONVOLATILE SEMICONDUCTOR MEMORY AND THE SAME MANUFACTURED THEREBY	2001-326288		22.11.2001
00-41159	2003-500918	20010525		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	WO02/09782 1		20021205
00-41238	2002-177482	20020618		METHOD AND DEVICE FOR READING DUAL BIT MEMORY CELL	2003- 68087		07.03.2003
01-40131	2003-131767	20030509		METHOD AND CIRCUIT FOR READING TWO BIT TYPE MEMORY CELL, AND SEMICONDUCTOR MEMORY DEVICE	2003-331592		21.11.2003
01-40674	2001-367052	20011130		SEMICONDUCTOR MEMORY AND ITS DRIVING METHOD	2003-173690		20.06.2003
01-41108	2002- 72350	20020315		SEMICONDUCTOR DEVICE	2003-270302		25.09.2003
01-41547	2002-319913	20021101		NONVOLATILE SEMICONDUCTOR MEMORY	2004-158052		03.06.2004
02-40035	2002-250932	20020829		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE AND DATA WRITING METHOD	2004-94987		25.03.2004
02-40036	2002-234857	20020812		VOLTAGE CONTROL CIRCUIT AND SEMICONDUCTOR MEMORY DEVICE	2004-79036		11.03.2004
02-40072	2003-122155	20030425		SYSTEM FOR CONTROLLING PRE- CHARGE LEVEL IN MEMORY DEVICE	2003-323796		14.11.2003
02-40253	2002- 80554	20020322		SEMICONDUCTOR MEMORY DEVICE	2003-281896		03.10.2003
02-40254	2002-234463	20020812		NONVOLATILE MEMORY HAVING TRAP LAYER	2004-79602		11.03.2004
02-40562	2002-319914	20021101		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-158053		03.06.2004
02-40878	2002-313954	20021029		SEMICONDUCTOR INTEGRATED CIRCUIT	2004-152341		27.05.2004
02-41001	2003- 9355	20030117		NONVOLATILE MULTI- LEVEL SEMICONDUCTOR MEMORY	2004-220728		05.08.2004

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02-41003	2003- 39689	20030218		NONVOLATILE SEMICONDUCTOR MEMORY	2004-253021		09.09.2004
02-41118	2003- 17466	20030127		SEMICONDUCTOR STORAGE DEVICE EQUIPPED WITH HIGH SPEED READOUT CIRCUIT	2004-227486		12.08.2004
02-41195	2002-269838	20020917		OPTICAL RECORDING MEDIUM FOR INSPECTION, METHOD FOR MANUFACTURING OPTICAL RECORDING MEDIUM FOR INSPECTION AND DISK DRIVE INSPECTION METHOD	2002-269838		20.09.2002
02-41217	2002-265065	20020911		MEMORY CIRCUIT HAVING REDUNDANCY CONSTITUTION	2004-103143		02.04.2004
02-41218	2002-268316	20020913		METHOD FOR DESIGNING SEMICONDUCTOR MEMORY DEVICE, AND SEMICONDUCTOR MEMORY DEVICE	2004-111443		08.04.2004
02-41219	2002-267097	20020912		SEMICONDUCTOR NONVOLATILE MEMORY WHICH HAS IMPROVED TRACKING CHARACTERISTIC	2004-103181		02.04.2004
02-41222	2002-268643	20020913		NONVOLATILE MEMORY CIRCUIT AND NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-110883		08.04.2004
02-41532	2003- 38636	20030217		STEP-UP CIRCUIT OF SMALL AREA WITH MULTISTAGE STRUCTURE	2004-247689		02.09.2004
02-41534	2003- 38642	20030217		CHARGE PUMP CIRCUIT WITH REDUCED AMPLITUDE OF STEP-UP VOLTAGE	2004-248475		02.09.2004
02-41535	2003- 73287	20030318		NONVOLATILE SEMICONDUCTOR MEMORY AND ITS OPERATION CONTROL METHOD	2004-280981		07.10.2004
02-41634	2002-370272	20021220		CONTROL METHOD OF NONVOLATILE SEMICONDUCTOR STORAGE DEVICE, AND NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-199833		15.07.2004
02-41637	2002-370273	20021220		METHOD OF CONTROLLING SEMICONDUCTOR DEVICE, AND THE SEMICONDUCTOR DEVICE	2004-199600		15.07.2004
02-41643	2002-370275	20021220		SEMICONDUCTOR DEVICE, SEMICONDUCTOR STORAGE DEVICE, AND TEST METHOD THEREFOR	2004-199834		15.07.2004
02-41644	2002-370276	20021220		SEMICONDUCTOR STORAGE DEVICE AND	2004-199835		15.07.2004

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				TEST METHOD THEREFOR			
02-41660	2002-348485	20021129		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE AND SEMICONDUCTOR DEVICE	2004-185670		02.07.2004
02-41661	2002-342677	20021126		SEMICONDUCTOR DEVICE AND ITS TESTING METHOD	2004-178672		24.06.2004
02-41696	2002-371126	20021220		SEMICONDUCTOR MEMORY DEVICE AND ITS CONTROL METHOD	2004-206740		22.07.2004
02-41698	2002-370277	20021220		CONTROL METHOD OF NONVOLATILE MEMORY, AND NONVOLATILE MEMORY	2004-199836		15.07.2004
02-41702	2003- 76960	20030320		SEMICONDUCTOR MEMORY DEVICE	2004-288260		14.10.2004
02-41719	2003- 87868	20030327		CHARGING PUMP CIRCUIT	2004-297922		21.10.2004
02-41730	2002-369554	20021220		SEMICONDUCTOR STORAGE DEVICE AND ITS CONTROL METHOD	2004-199825		15.07.2004
03-40053	PCT	20030428					
03-40222	2003-136269	20030514		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE AND METHOD FOR DETERMINING DATA	2004-047050		12.02.2004
99-40337	H11-293027	19991014		NON-VOLATILE MEMORY CIRCUIT RECORDING MULTI-BIT INFORMATION	2001-118390		27.04.2001
00-40018	2002-518468	20000803			WO02/01319 9		14.02.2002
00-40619	2002-551860	20001221		NONVOLATILE SEMICONDUCTOR MEMORY AND METHOD OF ERASURE	WO2002/050 843		20020627
00-40996	2001-123180	20010420		NONVOLATILE SEMICONDUCTOR MEMORY	2002-319287		31.10.2002
01-40129	2003-114392	20030418		METHOD AND SYSTEM FOR PROGRAMMING THRESHOLD VOLTAGE LEVEL AND SEMICONDUCTOR STORAGE DEVICE	2003-323793		14.11.2003
01-40756	2001-252400	20010823		MEMORY CONTROLLER FOR MULTI-VALUE CELL MEMORY	2003- 67260		07.03.2003
01-41067	2003- 51449	20030227		SYSTEM FOR SETTING MEMORY VOLTAGE THRESHOLD	2003-263895		19.09.2003
01-41415	2002-114145	20020417		NONVOLATILE SEMICONDUCTOR MEMORY AND METHOD OF MANUFACTURING THE SAME	2003-309192		31.10.2003
01-41516	2002- 53994	20020228		NONVOLATILE SEMICONDUCTOR MEMORY DEVICE	2003-257188		12.09.2003

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02-40420	2003-159556	20030604		NONVOLATILE SEMICONDUCTOR MEMORY	2004-273093		30.09.2004
02-41214	2002-268606	20020913		SEMICONDUCTOR MEMORY	2004-110881		08.04.2004
02-41221	2002-268317	20020913		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-110872		08.04.2004
98-40297	H11-209787	19990723		NON-VOLATILE MEMORY ENABLING ENCRPTION OF COMMAND	2001- 35171		09.02.2001
99-40506	2001-560823	20000216		NONVOLATILE MEMORY	2001- 861503 (WO 01/061503)		20010823
00-40048	2002-505627	20000629		SEMICONDUCTOR MEMORY DEVICE	WO02/001574		20020103
01-40842	2002- 12985	20020122		SEMICONDUCTOR NONVOLATILE MEMORY WITH FRAUDULENT READING PREVENTING FEATURE	2003-216499		31.07.2003
01-40865	2002- 45116	20020221		ERROR DETECTING/CORRECTING METHOD FOR MULTI-LEVEL SEMICONDUCTOR MEMORY, AND MULTI-LEVEL SEMICONDUCTOR MEMORY HAVING ERROR DETECTING/CORRECTING FUNCTION	2003- 36693		07.02.2003
01-41056	2001-322813	20011019		NONVOLATILE SEMICONDUCTOR MEMORY AND CONTROL METHOD THEREFOR	2003-132688		09.05.2003
01-41288	2002-120548	20020423		LOW TEMPERATURE TEST APPARATUS FOR SEMICONDUCTOR DEVICE USING ELECTRONIC COOLING ELEMENT	2003-315406		06.11.2003
01-41306	2002- 4150	20020111		MEMORY DEVICE	2002-328836		15.11.2002
02-40528	2002-231825	20020808		METHOD FOR CONTROLLING SEMICONDUCTOR MEMORY DEVICE AND SEMICONDUCTOR MEMORY DEVICE	2004-71105		04.03.2004
02-41215	2002-268315	20020913		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-110871		08.04.2004
02-41410	PCT/JP2003/ 001971	20030224		VOLTAGE SENSING CIRCUIT, SEMICONDUCTOR DEVICE, METHOD FOR CONTROLLING VOLTAGE SENSING CIRCUIT	WO20040752 02		20040902

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02-41434	PCT/JP2003/001739	20030218		SEMICONDUCTOR5 STORAGE DEVICE AND SEMICONDUCTOR STORAGE DEVICE READ OUT METHOD	WO2004075199		20040902
02-41531	2004-568757	20030227					
02-41615	2004-568776	20030228					
02-41642	2002-370274	20021220		SEMICONDUCTOR DEVICE AND ITS TESTING METHOD	2004-198367		15.07.2004
02-41651	2005-500549	20030605					
02-41655	2005-500550	20030605					
02-41656	2004-571303	20030430					
02-41690	2004-569330	20030311					
02-41701	2002-370278	20021220		NONVOLATILE MEMORY AND WRITING METHOD THEREFOR	2004-199837		15.07.2004
02-41729	2002-377039	20021226		SEMICONDUCTOR MEMORY AND CONTROL METHOD FOR SEMICONDUCTOR MEMORY	2004-206832		22.07.2004
02-41828	2002-374366	20021225		STORAGE METHOD AND STORAGE DEVICE FOR NONVOLATILE MEMORY	2004-206381		22.07.2004
03-40052	2003- 50264	20030227		SEMICONDUCTOR MEMORY DEVICE	2004-259385		16.09.2004
03-40067	PCT	20030424					
03-40184	PCT	20030417					
03-40729	2005-500563	20030605					
91P08819	1991-240040(H03)	19910919	26.09.2003	SEMICONDUCTOR MEMORY	H05-81887	3476479	02.04.1993
99-40900	JP2000/004801	20000717		SYSTEM FOR UTILIZING DYNAMIC REFERENCE BY TWO-BIT CELL MEMORY	WO2002007215		
01-41290	2003-274071	20030714		SYSTEM FOR UTILIZING DYNAMIC REFERENCE BY TWO-BIT CELL MEMORY	2004-039234		05.02.2004
02-41032	2002-267680	20020913		SEMICONDUCTOR MEMORY FOR NORMALLY PERFORMING REPLACEMENT WITH REDUNDANCY CELL ARRAY	2004-110861		08.04.2004
02-40906	2003-380841	Outsourced 14.08.05 20031111 Priority Date 20030606)		NONVOLATILE SEMICONDUCTOR STORAGE DEVICE	2004-362729		24.12.2004

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00-40183	2000-141072	20000515		NON-VOLATILE SEMICONDUCTOR MEMORY, AND DATA HOLDING METHOD FOR NON-VOLATILE SEMICONDUCTOR MEMORY	2001-325793		22.11.2001
99-40134	H11-300401	19991022	2003.05.16	NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2001-118943	3430084	
91P10042	H03-279308	19911025		NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND MANUFACTURE THEREOF	H05-121702		
99-40225	H11-266074	19990920		SEMICONDUCTOR INTEGRATED-CIRCUIT DEVICE AND MANUFACTURING METHOD THEREOF	2001-094076		
98-02045	H10-345307	19981204		MANUFACTURE OF SEMICONDUCTOR DEVICE	2000-174235		
99-40258	H11-266075	19990920	2004.01.16	NONVOLTAILE SEMICONDUCTOR STORAGE, WRITING METHOD AND READING METHOD THEREFOR	2001-093995	3513056	
00-41250	2001-076585	20010316		SEMICONDUCTOR DEVICE AND ITS FABRICATING METHOD	2002-280464		
01-40212	2001-094582	20010329		SEMICONDUCTOR MEMORY AND ITS DRIVING METHOD	2002-299473		
97-01109	H09-184773	19970710		NON-VOLATILE SEMICONDUCTOR DEVICE AND MANUFACTURE THEREOF	H11-031798		
97-05686	H10-066898	19980317		SEMICONDUCTOR DEVICE AND ITS MANUFACTURE	H11-265947		
97-07264	H10-128682	19980512		MANUFACTURE OF SEMICONDUCTOR DEVICE	H11-330274		
02-41423	2003-030977	20030207		NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND ITS MANUFACTURING METHOD	2004-241698		
91P10155	H03-277488	19911024	2003.06.27	TEST METHOD FOR SEMICONDUCTOR DEVICE	1993120900	3444902	
98-01577	H10-308082	19981029		MANUFACTURE OF SEMICONDUCTOR STORAGE DEVICE	2000-133727		
98-02046	H10-349028	19981208		SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURE THEREOF	2000-174237		
00-40023	2000-209230	20000711		SEMICONDUCTOR STORAGE DEVICE AND ITS MANUFACTURING METHOD	2002-026155		

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00-40405	2000-276398	20000912		SEMICONDUCTOR STORAGE DEVICE AND ITS CONTROL METHOD	2002-093925		
94-03318	H06-223270	19940919		FLASH MEMORY AND MANUFACTURE THEREOF	H08-088287		
02-40764	2002-266995	20020912		SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF	2004-104009		
02-50911	2002-230062	20020807		SEMICONDUCTOR STORAGE DEVICE AND ITS MANUFACTURING METHOD	2004-071877		
02-41448	2003-027514	20030204		SEMICONDUCTOR STORAGE DEVICE AND MANUFACTURING METHOD THEREOF	2004-241503		
02-41913	2003-104841	20030409		MANUFACTURING METHOD OF SEMICONDUCTOR STORAGE DEVICE	2004-311803		
02-41452	2003-060360	20030306		MANUFACTURING METHOD OF SEMICONDUCTOR STORAGE DEVICE	2004-273643		
01-40603	2001-260702	20010830		STATIC RANDOM ACCESS MEMORY WITH NON-VOLATILE DATA HOLDING FUNCTION AND ITS OPERATING METHOD	2003-068982		
02-40033	2002-135688	20020510		NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2003-332469		
00-41147	2000-351444	20001117		NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND MANUFACTURING METHOD THEREOF	2002-158298		
00-41153	2001-031320	20010207		SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE SAME	2002-237540		
97-7547	1997-350393 (H09)	19971219	2003.12.12	MANUFACTURE OF SEMICONDUCTOR DEVICE	1999186261	3500564	
90P10187	1990-279832 (H02)	19901018	1997.04.25	MANUFACTURE OF SEMICONDUCTOR DEVICE	1992154124	2639202	
96-07070	H08-318130	19961128	2003.06.20	MANUFACTURE OF SEMICONDUCTOR DEVICE	H10-163456	3442596	
02-41600	2002-354049	20021205	-	NONVOLATILE SEMICONDUCTOR MEMORY	2004-158810	-	
91P07591	H03-201033	19910812	1997.11.21	MANUFACTURE OF SEMICODUCTOR DEVICE	H05-048046	2720645	
02-40107	2002-146184	20020521	-	NON-VOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2003-338566	-	

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02-40193	2002-255919	20020830	-	METHOD FOR MANUFACTURING MEMORY INTEGRATED CIRCUIT DEVICE	2004-095904	-	2005.08.25
02-41716	2003-132041	20030509	-	NONVOLATILE SEMICONDUCTOR MEMORY DEVICE AND METHOD OF MANUFACTURING THE SAME	2004-056095	-	
05-80085	2005- 96274	20050329		SEMICONDUCTOR DEVICE	2005-229128		